

TENTATIVE TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

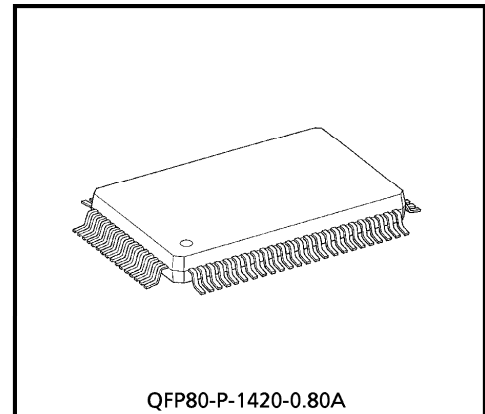
TC9284BF

CD SINGLE CHIP PROCESSOR WITH BUILT-IN 1BIT DA CONVERTER

The TC9284BF is a single chip processor for sync separation protection/synchronization, EFM demodulation, error correction/interpolation, microcomputer interface, CLV servo a focus tracking servo in CD player system. And, built-in 1bit DA converter. In combination with the TA8190F/TA8191F/TA2031F/TA2035F/TA2065F/TA2077F, which are focus tracking servo LSI, a CD player system can be composed very simply.

FEATURES

- Positive sync pattern detection, sync signal protection and synchronization.
- Built-in EFM demodulation and subcode demodulation circuit.
- Has the correction capacity of single and double corrections for C1 and C2 correcting units, respectively, using CIRC correction theoretical format.
- Jitter absorbing capacity of ± 5 frames.
- Built-in 16K RAM.
- Built-in digital out circuit.
- Smooth muting through zero cross detection.
- Read timing free subcode Q data.
- Built-in data slicer and analog PLL (free-adjustment VCO adopted) circuit.
- Focus/tracking loop gain auto adjusting function incorporated.
- Built-in AFC and APC circuits for disc motor CLV servo.
- Built-in focus tracking servo control circuit.
- Tracking search control capable of coping with all modes.
- Built-in 1bit DA converter.
Function of DA converter.
 - (1) Built-in 8-time oversampling digital filter.
 - (2) Built-in soft mute function.
- Built-in microcomputer interface circuit.
- Double speed play is possible.
- In CMOS structure, high speed and low power dissipation.
- 80 pin flat package.



QFP80-P-1420-0.80A

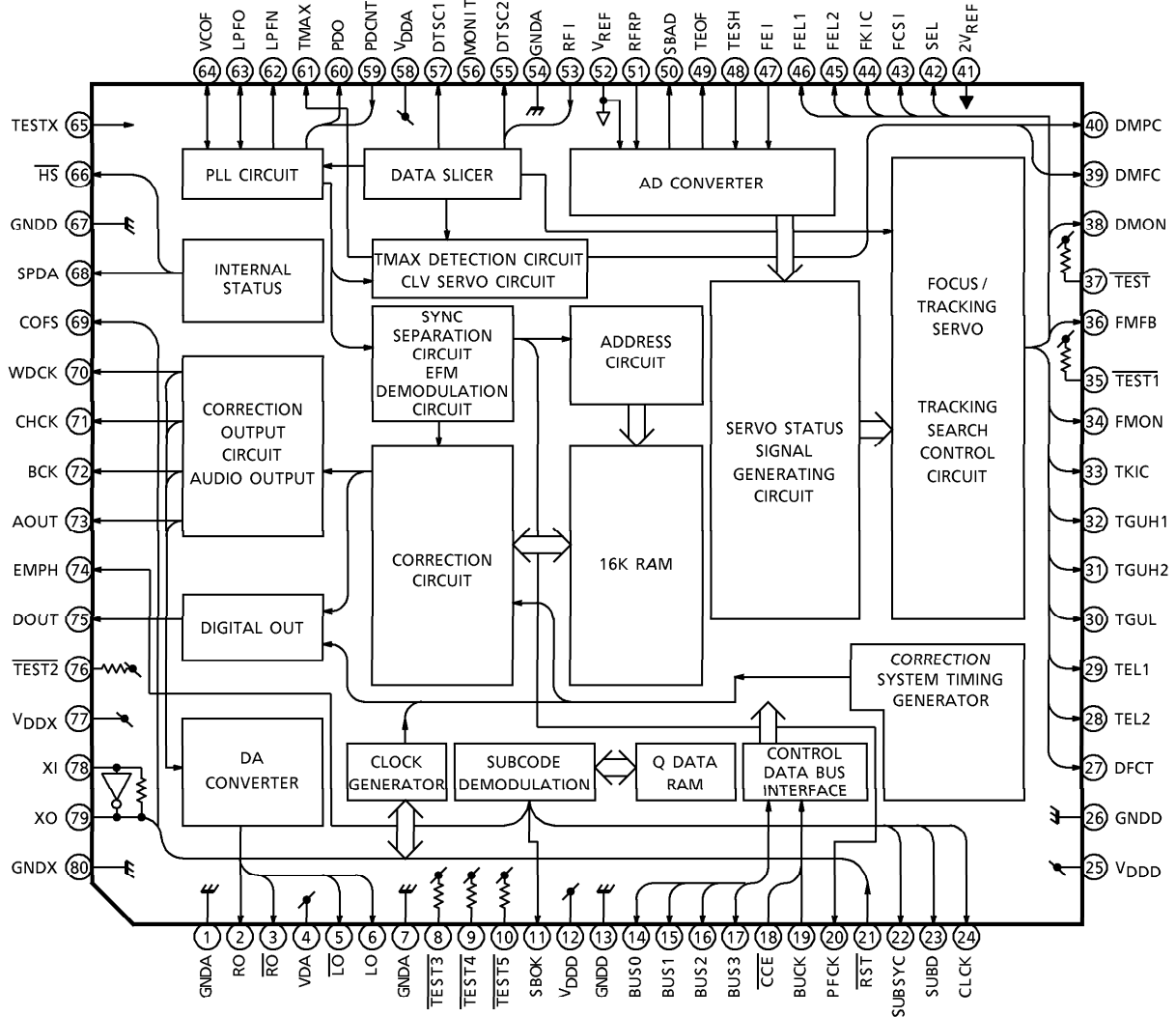
Weight : 1.57g (Typ.)

980508EBA2

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PIN CONNECTION / BLOCK DIAGRAM

(Top view)



PIN FUNCTION

PIN No.	SYMBOL	I/O	FUNCTIONAL DESCRIPTION	REMARKS
1	GNDA	—	Analog grand terminal for DA converter (R channel)	—
2	RO	O	R channel data forward output terminal.	—
3	\overline{RO}	O	R channel data reverse output terminal.	—
4	V _{DA}	—	Analog power supply terminal for DA converter.	—
5	\overline{LO}	O	L channel data reverse output terminal.	—
6	LO	O	L channel data forward output terminal.	—
7	GNDA	—	Analog grand terminal for DA converter (L channel)	—
8	$\overline{TEST3}$	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor
9	$\overline{TEST4}$	I	Test terminal. Normally, keep at "H" level or open.	
10	$\overline{TEST5}$	I	Test terminal. Normally, keep at "H" level or open.	
11	SBOK	O	Subcode Q data CRC check adjusting result output terminal. The adjusting result is OK at "H" level.	—
12	V _{DDD}	—	Digital supply voltage terminal. (+5V)	—
13	GNDD	—	Digital ground terminal.	—
14 5 17	BUS0 5 BUS3	I/O	Command and data sending/receiving input/output terminals.	Schmitt input Open drain output With pull-up resistor
18	\overline{CCE}	I	Command and data sending/receiving chip enable signal input terminal. The bus line becomes active at "L" level.	Schmitt input
19	BUCK	I	Command and data sending/receiving clock input terminal.	
20	PFCK	O	Regeneration system frame periodic signal output terminal. 7.35kHz	—
21	\overline{RST}	I	Reset input terminal. The internal system is reset at "L" level.	With pull-up resistor
22	SUBSYC	O	Subcode sync signal output terminal.	—
23	SUBD	O	Subcode P~W output terminals.	—
24	CLCK	I	Subcode P~W data readout clock input terminal.	—
25	V _{DDD}	—	Digital supply voltage terminal.	—
26	GNDD	—	Digital ground terminal.	—
27	DFCT	O	Defect detection signal output terminal. V _{REF} when defect is detected. Normally, HiZ.	—
28	TEL2	O	Tracking gain adjusting analog switch output terminals V _{REF} or HiZ.	—
29	TEL1			
30	TGUL	O	Tracking servo loop low frequency phase compensator change-over analog switch output terminal. HiZ (gain up) when detecting shock. Normally, V _{REF} .	—

PIN FUNCTION

PIN No.	SYMBOL	I/O	FUNCTIONAL DESCRIPTION	REMARKS																
31	TGUH2	O	Tracking servo loop middle/high frequency phase compensator change-over analog switch output terminals.	—																
32	TGUH1		HiZ (gain up) when detecting shock. Normally, V _{REF} . TGUH1 is used at normal regeneration and TGUH2 is used at double speed regeneration.																	
33	TKIC	O	Tracking actuator kick signal output terminal. Kicks in the outer circumferential direction at "H" level and in the inner circumferential direction at "L" level.	3-state output																
34	FMON	O	Feed servo ON/OFF analog switch output terminals. Servo on at "HiZ". Servo off at "V _{REF} ".	—																
35	TEST1	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor																
36	FMFB	O	Feed motor FWD/BWD feeding control signal output terminal. Feed in the outer circumferential direction at "H" level and in the inner circumferential direction at "L" level.	3-state output																
37	TEST	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor																
38	DMON	O	Disc motor driving circuit gain change-over analog switch output terminal.	—																
39	DMFC	O	Disc motor CLV servo AFC signal output terminal.	3-state output																
			<table border="1"> <thead> <tr> <th>COMMAND</th> <th>DMFC OUTPUT</th> <th>OPERATION</th> </tr> </thead> <tbody> <tr> <td>DMFK</td> <td>H</td> <td>Motor acceleration</td> </tr> <tr> <td>DMSV</td> <td>PWM</td> <td>CLV servo ON</td> </tr> <tr> <td>DMBK</td> <td>L</td> <td>Motor deceleration</td> </tr> <tr> <td>DMOFF</td> <td>V_{REF}</td> <td>CLV servo OFF</td> </tr> </tbody> </table>		COMMAND	DMFC OUTPUT	OPERATION	DMFK	H	Motor acceleration	DMSV	PWM	CLV servo ON	DMBK	L	Motor deceleration	DMOFF	V _{REF}	CLV servo OFF	
			COMMAND		DMFC OUTPUT	OPERATION														
			DMFK		H	Motor acceleration														
			DMSV		PWM	CLV servo ON														
DMBK	L	Motor deceleration																		
DMOFF	V _{REF}	CLV servo OFF																		
40	DMPC	O	Disc motor CLV servo APC signal output terminal.	3-state output																
41	2V _{REF}	I	Double times reference voltage input terminal. (V _{REF} × 2)	—																
42	SEL	O	Servo mode indicating signal output terminal.	3-state output																
			<table border="1"> <thead> <tr> <th>SEL</th> <th>LD ON/OFF</th> <th>FOCUS SERVO</th> <th>OPERATION</th> </tr> </thead> <tbody> <tr> <td>L</td> <td>OFF</td> <td>OFF</td> <td>LD OFF</td> </tr> <tr> <td>HiZ</td> <td>ON</td> <td>OFF</td> <td>Focus Search</td> </tr> <tr> <td>H</td> <td>ON</td> <td>ON</td> <td>Normal play, etc. Focus Servo ON : FOK)</td> </tr> </tbody> </table>		SEL	LD ON/OFF	FOCUS SERVO	OPERATION	L	OFF	OFF	LD OFF	HiZ	ON	OFF	Focus Search	H	ON	ON	Normal play, etc. Focus Servo ON : FOK)
			SEL		LD ON/OFF	FOCUS SERVO	OPERATION													
			L		OFF	OFF	LD OFF													
HiZ	ON	OFF	Focus Search																	
H	ON	ON	Normal play, etc. Focus Servo ON : FOK)																	

PIN No.	SYMBOL	I/O	FUNCTION DESCRIPTION	REMARKS												
43	FCSI	O	Focus actuator driving signal output terminal in the focus search mode.	3-state output												
			<table border="1"> <thead> <tr> <th>COMMAND</th> <th>FCSI OUTPUT</th> <th>OPERATION</th> </tr> </thead> <tbody> <tr> <td>FORST</td> <td>H</td> <td>Lens gets for away from disc</td> </tr> <tr> <td>FOSET</td> <td>L</td> <td>Lens gets near disc</td> </tr> <tr> <td>Others</td> <td>HiZ</td> <td>Other than focus search</td> </tr> </tbody> </table>		COMMAND	FCSI OUTPUT	OPERATION	FORST	H	Lens gets for away from disc	FOSET	L	Lens gets near disc	Others	HiZ	Other than focus search
			COMMAND		FCSI OUTPUT	OPERATION										
			FORST		H	Lens gets for away from disc										
FOSET	L	Lens gets near disc														
Others	HiZ	Other than focus search														
44	FKIC	O	Focus actuator driving signal output terminal in the focus gain adjusting mode.	3-state output												
			<table border="1"> <thead> <tr> <th>COMMAND</th> <th>FKIC OUTPUT</th> <th>OPERATION</th> </tr> </thead> <tbody> <tr> <td>FGASR</td> <td>H</td> <td>Lens gets for away from disc</td> </tr> <tr> <td>FGASS</td> <td>L</td> <td>Lens gets near disc</td> </tr> <tr> <td>Others</td> <td>HiZ</td> <td>Other than focus adjustment</td> </tr> </tbody> </table>		COMMAND	FKIC OUTPUT	OPERATION	FGASR	H	Lens gets for away from disc	FGASS	L	Lens gets near disc	Others	HiZ	Other than focus adjustment
			COMMAND		FKIC OUTPUT	OPERATION										
			FGASR		H	Lens gets for away from disc										
FGASS	L	Lens gets near disc														
Others	HiZ	Other than focus adjustment														
45	FEL2	O	Focus again adjusting analog switch output terminals.	—												
46	FEL1															
47	FEI	I	Focus error signal input terminal.	Analog output												
48	TESH	I	Tracking error signal input sample holding analog switch input terminal.	—												
49	TEOF	O	Tracking servo operation ON/OFF analog switch output terminal. V _{REF} when the tracking servo is OFF.	—												
50	SBAD	I	Sub beam adding signal input terminal.	Analog input												
51	RFRP	I	RF ripple signal input terminal.													
52	VREF	I	Reference voltage input terminal. (+2.1V)	—												
53	RFI	I	RF signal input terminal.	Analog input												
54	GNDA	—	Analog ground terminal.	—												
55	DTSC2	O	Data slice control EFM signal passive output terminal.	—												
56	MONIT	O	Internal signal (EFMO, PLCK, LOCK and MBOV) output terminal. Selected by command.	—												
57	DTSC1	O	Data slice control EFM signal negative output terminal.	—												
58	VDDA	—	Analog supply voltage terminal. (+5V)	—												
59	PDCNT	I	PDO output control terminal. At "L" level, PDO output is made to HiZ by force.	—												
60	PDO	O	Phase error signal output terminal between EFM signal and PLCK.	3-state output												

PIN No.	SYMBOL	I/O	FUNCTIONAL DESCRIPTION	REMARKS								
61	TMAX	O	TMAX signal output terminal. Hiz at time of system clock.	3-state output								
			<table border="1"> <thead> <tr> <th>TMAX PERIOD</th> <th>TMAX OUTPUT</th> </tr> </thead> <tbody> <tr> <td>Longer than specified period</td> <td>L</td> </tr> <tr> <td>Shorter than specified period</td> <td>H (2V_{REF})</td> </tr> <tr> <td>Specified period</td> <td>HiZ</td> </tr> </tbody> </table>		TMAX PERIOD	TMAX OUTPUT	Longer than specified period	L	Shorter than specified period	H (2V _{REF})	Specified period	HiZ
			TMAX PERIOD		TMAX OUTPUT							
			Longer than specified period		L							
Shorter than specified period	H (2V _{REF})											
Specified period	HiZ											
62	LPFN	I	LPF amplifier inverting input terminal for PLL.	—								
63	LPFO	O	LPF amplifier output terminal for PLL.	—								
64	VCOF	I	VCO filter terminal.	—								
65	TESTX	I	Test terminal.	—								
66	\overline{HS}	O	Double speed monitor output terminal. Double speed operation at "L" level.	—								
67	GNDD	—	Digital ground terminal.	—								
68	SPDA	O	Processor status signal output terminal. Correction process judging result, memory buffer capacity, etc.	—								
69	COFS	O	Correction system frame periodic signal output terminal. 7.35kHz.	—								
70	WDCK	O	Word clock output terminal. Normally, 88.2kHz.	—								
71	CHCK	O	Channel clock output terminal. Normally, 44.1kHz.	—								
72	BCK	O	Bit clock output terminal. Normally, 1.4112MHz.	—								
73	AOUT	O	Audio data output terminal.	—								
74	EMPH	O	Emphasis ON/OFF indication signal output terminal. Emphasis ON at "H" level.	—								
75	DOUT	O	Digital out output terminal.	—								
76	$\overline{TEST2}$	I	Test terminal. Normally, keep at "H" level or open.	With pull-up resistor								
77	VDDX	O	Oscillator supply voltage terminal.	—								
78	XI	I	Crystal oscillator connecting terminal.									
79	XO	O										
80	GNDX	O	Oscillator grand terminal.	—								

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Power Supply Voltage	V _{DD}	-0.3~6.0	V
Input Voltage	V _{IN}	-0.3~V _{DD} +0.3	V
Power Dissipation	P _D	1250	mW
Operating Temperature	T _{opr}	-35~85	°C
Storage Temperature	T _{stg}	-55~150	°C

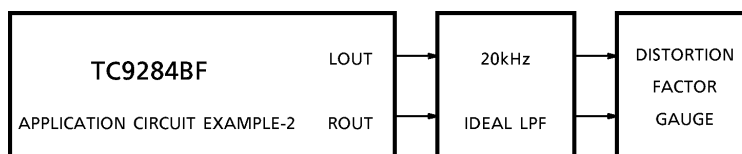
ELECTRICAL CHARACTERISTICS

(Unless otherwise specified, V_{DD} = 5V, 2V_{REF} = 4.2V, V_{REF} = 2.1V, Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Operating Supply Voltage	V _{DD}	—	Ta = -35~85°C	4.5	5.0	5.5	V	
Operating Supply Current	I _{DD}	—	XI = 16.9344MHz In normal mode	—	40	70	mA	
Input Voltage	"H" Level	V _{IH} (1)	Whole input terminals except BUS0~3, BUCK and CCE	3.5	—	V _{DD} +0.3	V	
	"L" Level	V _{IL} (1)		0	—	1.5		
	"H" Level	V _{IH} (2)		BUS0~3, BUCK, CCE (Schmitt input)	4.0	—		V _{DD} +0.3
	"L" Level	V _{IL} (2)			0	—		1.0
Input Current	"H" Level	I _{IH}	V _{IH} = 5V CMOS input terminals except analog input terminal	—	—	1.0	μA	
	"L" Level	I _{IL}		V _{IL} = 0V	-1.0	—		—
Try State Leak Current	"H" Level	I _{TLH}	V _{IH} = 5V V _{IL} = 0V	—	—	1.0	μA	
	"L" Level	I _{TLL}		-1.0	—	—		
Output Current	"H" Level	I _{OH} (1)	V _{OH} = 4.6V WDCK, CHCK, BCK, AOUT, DOUT, XO V _{OUT} = V _{DD}	—	—	-2.0	mA	
	"L" Level	I _{OL} (1)		V _{OL} = 0.4V	2.0	—		—
	"H" Level	I _{OH} (2)	V _{OH} = 4.6V SBOK, PFCK, SUBSYN, SUBD, CLCK, SEL, HS, FCSI, FKIC, PDCNT, MONIT, COFS, SPDA V _{OUT} = V _{DD}	—	—	-0.5		
	"L" Level	I _{OL} (2)		V _{OL} = 0.4V	1.0	—		—
	"H" Level	I _{OH} (3)	V _{OH} = 3.8V TKIC, FMFB, DMFC, DMPC, TMAX V _{OUT} = 2V _{REF}	—	—	-0.4		
	"L" Level	I _{OL} (3)		V _{OL} = 0.4V	1.0	—		—
	"H" Level	I _{OH} (4)	V _{OH} = 3.8V PDO V _{OUT} = 2V _{REF}	—	—	-1.0		
	"L" Level	I _{OL} (4)		V _{OL} = 0.4V	1.0	—		—
Analog Switch OFF Current	"H" Level	I _{OFH}	V _{IH} = 5V V _{IL} = 0V	—	—	1.0	μA	
	"L" Level	I _{OFL}		-1.0	—	—		

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Analog Switch ON Resistance	R _{ON} (1)	—	FEL1/2, TEL1/2, FMON, TGUL, TGUH1/2, DFCT, TEOF, DMON	—	—	0.3	kΩ
	R _{ON} (2)		TESH	—	—	0.6	
Pull-up Resistance	R _{UP} (1)	—	RST	—	50	—	kΩ
	R _{UP} (2)		TEST, TEST1~5	—	30	—	
	R _{UP} (3)		BUS3~0	8	—	—	
Oscillation Amplifier Feedback Resistance	R _N	—	XI XO between	2	4	6	kΩ
Operating Frequency Ratio	f _{op}	—	XI	6	—	28	MHz
Total Harmonic Distortion + Noise	THD + N	1	1kHz sine wave Full-scale input	—	-85	-80	dB
S/N Ratio	S/N	1		90	98	—	dB
Dynamic Range	DR	1	1kHz sine wave -60dB input conversion	90	95	—	dB
Cross-talk	CT	1	1kHz sine wave Full-scale input	—	-95	-85	dB

TEST CIRCUIT 1 : Application circuit example-2 is used.



LPF : SHIBASOKU 725C BUILT-IN FILTER
 DISTORTION FACTOR GAUGE : SHIBASOKU 725C OR EQUIVALENT

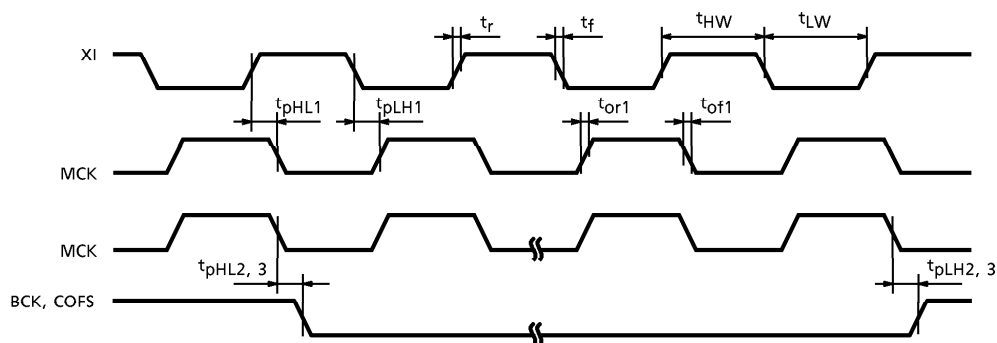
MEASURING ITEM	DISTORTION FACTOR GAUGE FILTER SETTING A WEIGHT
THD + N, CT	OFF
S/N, DR	ON

A WEIGHT : IEC-A OR EQUIVALENT

AC CHARACTERISTICS

(1) Clock system timing

CHARACTERISTIC		SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT		
Clock Pulse Width	"H" Level	t_{HW}	—	XI input	18	—	—	ns		
	"L" Level	t_{LW}			18	—	—			
Input Rising Time		t_r			—	—	—		10	ns
Input Falling Time		t_f			—	—	—		10	
Transfer Time (1)	"H" Level	t_{pHL1}	—	XI→MCK	—	—	60	ns		
	"L" Level	t_{pLH1}			—	—	60			
Transfer Time (2)	"H" Level	t_{pHL2}	—	MCK→BCK	—	—	60			
	"L" Level	t_{pLH2}			—	—	60			
Transfer Time (3)	"H" Level	t_{pHL3}	—	MCK→COFS	—	—	100			
	"L" Level	t_{pLH3}			—	—	100			
Output Rising Time (1)		t_{or1}	—	MCK, BCK	—	—	15	ns		
Output Falling Time (1)		t_{of1}			—	—	—		15	
Output Rising Time (2)		t_{or2}	—	COFS	—	—	40	ns		
Output Falling Time (2)		t_{of2}			—	—	—		40	

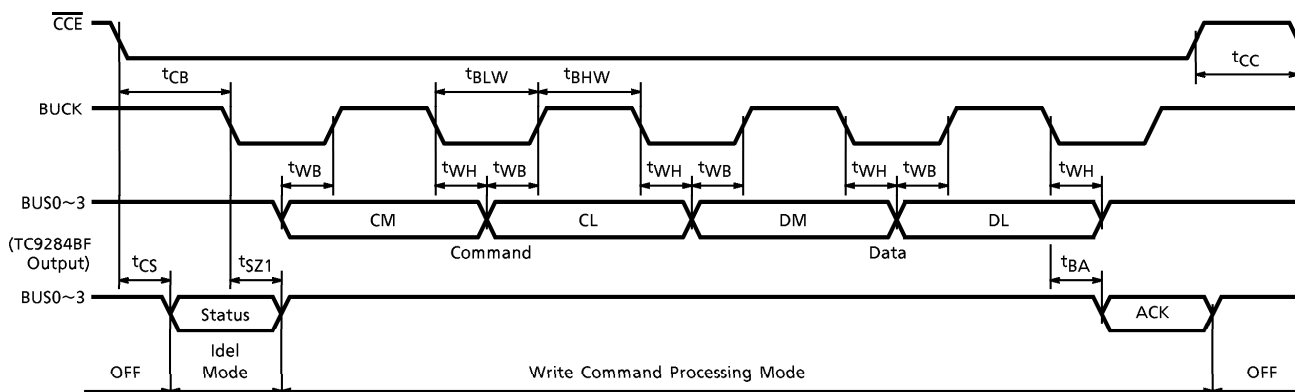


(2) Microcomputer interface timing

CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Clock Pulse Width (1)	"H" Level	t_{BHW}	BUCK	10	—	—	μS
	"L" Level	t_{BLW}		10	—	—	
Clock Pulse Width (2)	"H" Level	t_{CC}	\overline{CCE}	6	—	—	μS
Delay Time (1)	t_{CB}	—	$\overline{CCE} \rightarrow BUCK$	—	—	6	μS
Delay Time (2)	t_{WB}	—	Command Data \rightarrow BUCK	0	—	—	
Delay Time (3)	t_{CS}	—	$\overline{CCE} \rightarrow$ Status Output	—	—	6	
Delay Time (4)	t_{BC}	—	BUCK $\rightarrow \overline{CCE}$	6	—	—	
Setup Time (1)	t_{RD}	—	BUCK \rightarrow Read Data Output	—	—	6	μS
Setup Time (2)	t_{BA}	—	BUCK \rightarrow ACK, Each Parity Output	—	—	6	
Hold time (1)	t_{SZ1}	—	BUCK \rightarrow Status, ACK, Each Parity Output	—	—	6	μS
Hold time (2)	t_{SZ2}	—	$\overline{CCE} \rightarrow$ Status Output	—	—	6	
Hold time (3)	t_{WH}	—	BUCK \rightarrow Command Data	6	—	—	

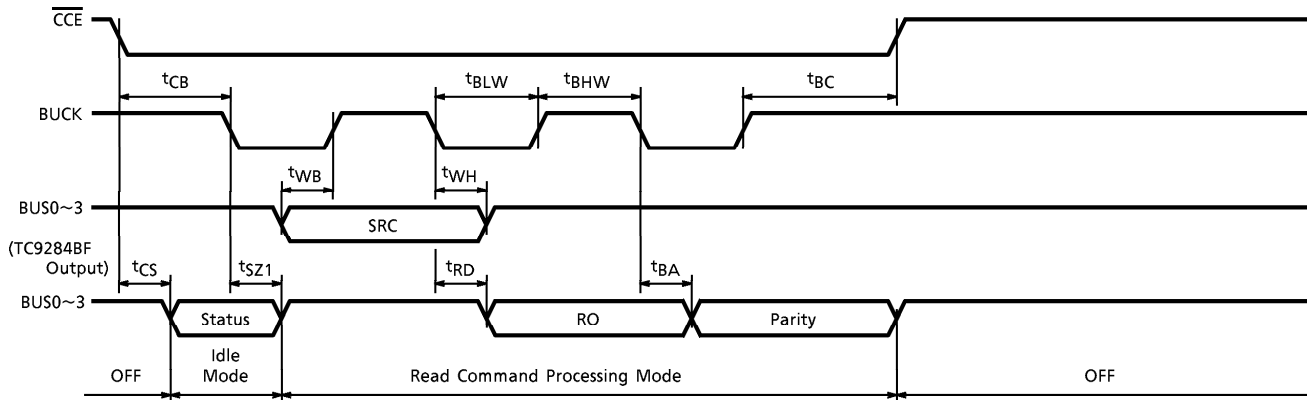
(a) Write command processing mode

(Microcomputer output)



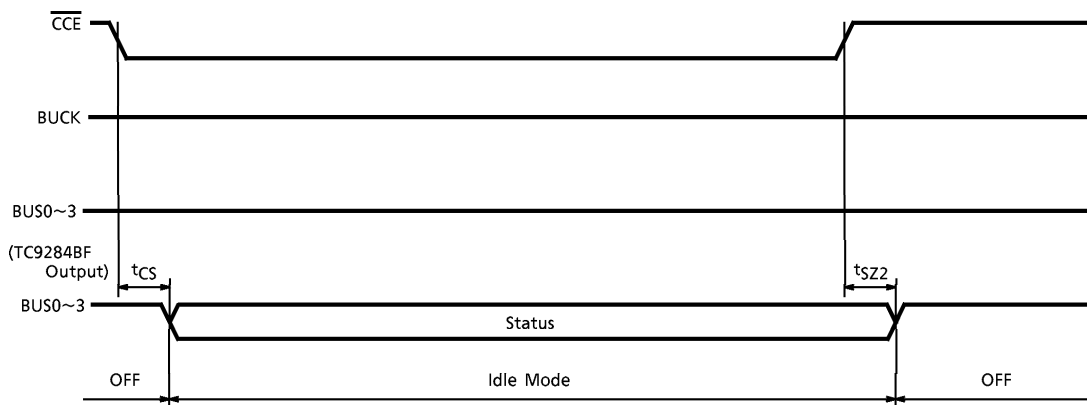
(b) Read command processing mode

(Microcomputer Output)



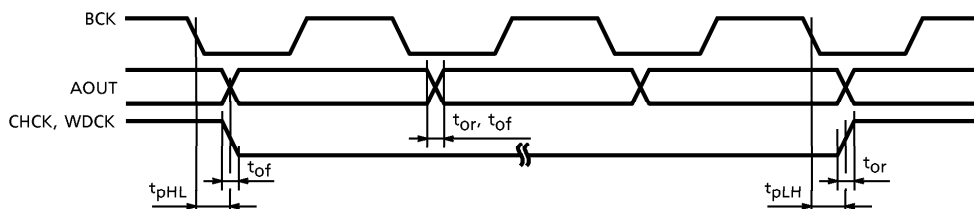
(c) Idle mode

(Microcomputer Output)



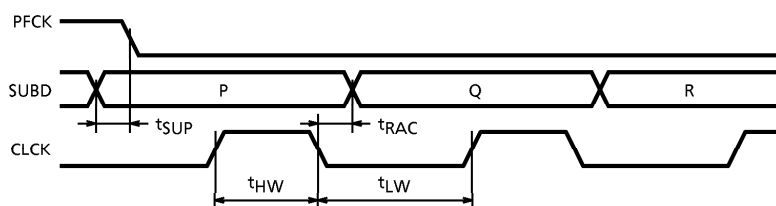
(3) Data output timing

CHARACTERISTIC		SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t_{pHL}	—	BCK→AOUT, WDCK, CHCK	—	—	30	ns
	"L" Level	t_{pLH}	—		—	—	30	
Output Rising Time		t_{or}	—	AOUT, WDCK, CHCK	—	—	15	ns
Output Falling Time		t_{of}	—		—	—	15	



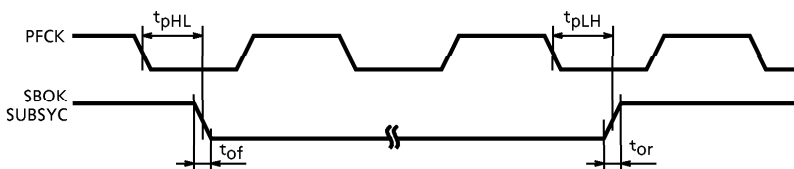
(4) Output timing for subcode P~W

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Clock Pulse Width	"H" Level	t_{HW}	CLCK	2	—	—	μS
	"L" Level	t_{LW}		2	—	—	
Setup Time	t_{SUP}	—	PFCK→SUBD	0.4	—	—	μS
Read Access Time	t_{RAC}	—	CLCK→SUBD	1.2	—	—	



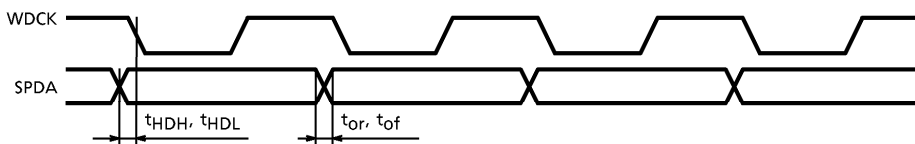
(5) Output timing for subcode Q

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t_{pHL}	PFCK→SBOK, SUBSYC	-50	—	200	ns
	"L" Level	t_{pLH}		-50	—	200	
Output Rising Time	t_{or}	—	SBOK, SUBSYC	—	—	40	ns
Output Falling Time	t_{of}	—		—	—	40	



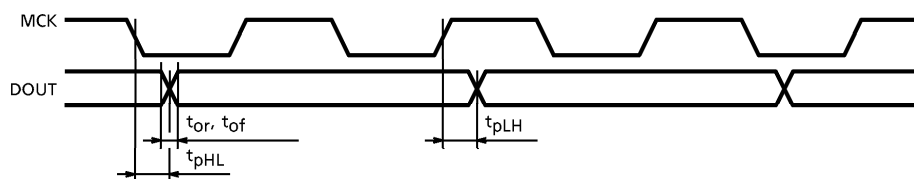
(6) Status signal output timing

CHARACTERISTIC	SYMBOL	TEST CIRCUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Hold Time	"H" Level	t_{HDH}	WDCK→SPDA	—	—	200	ns
	"L" Level	t_{HDL}		—	—	200	
Output Rising Time	t_{or}	—	SPDA	—	—	40	ns
Output Falling Time	t_{of}	—		—	—	40	

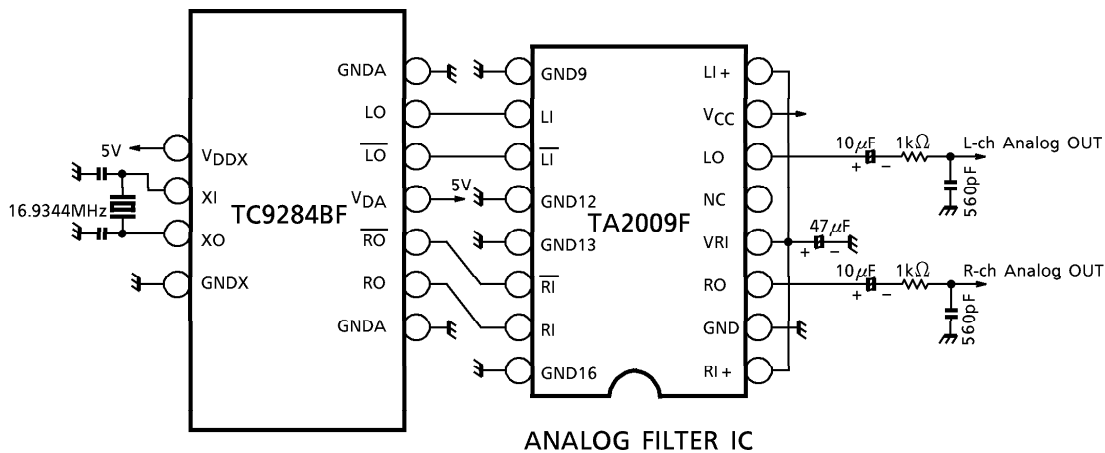


(7) Digital out output timing

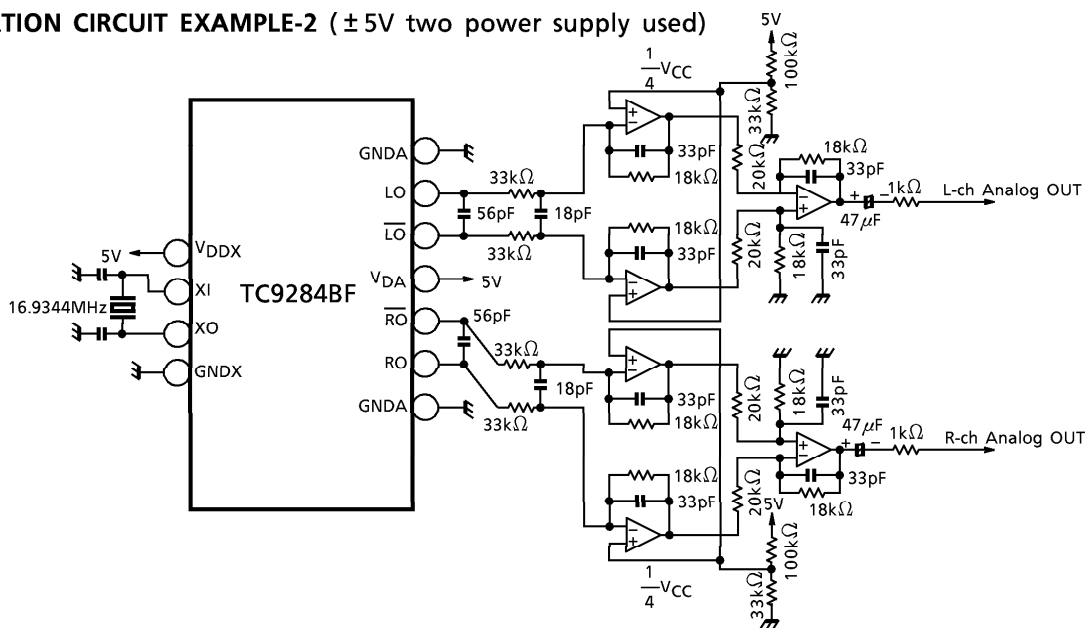
CHARACTERISTIC	SYMBOL	TEST CIR-CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transfer Time	"H" Level	t_{pHL}	MCK→DOUT	—	—	60	ns
	"L" Level	t_{pLH}		—	—	60	
Output Rising Time	t_{or}	—	DOUT	—	—	14	ns
Output Falling Time	t_{of}	—		—	—	14	



APPLICATION CIRCUIT EXAMPLE-1 (+5V single power supply used)



APPLICATION CIRCUIT EXAMPLE-2 ($\pm 5V$ two power supply used)

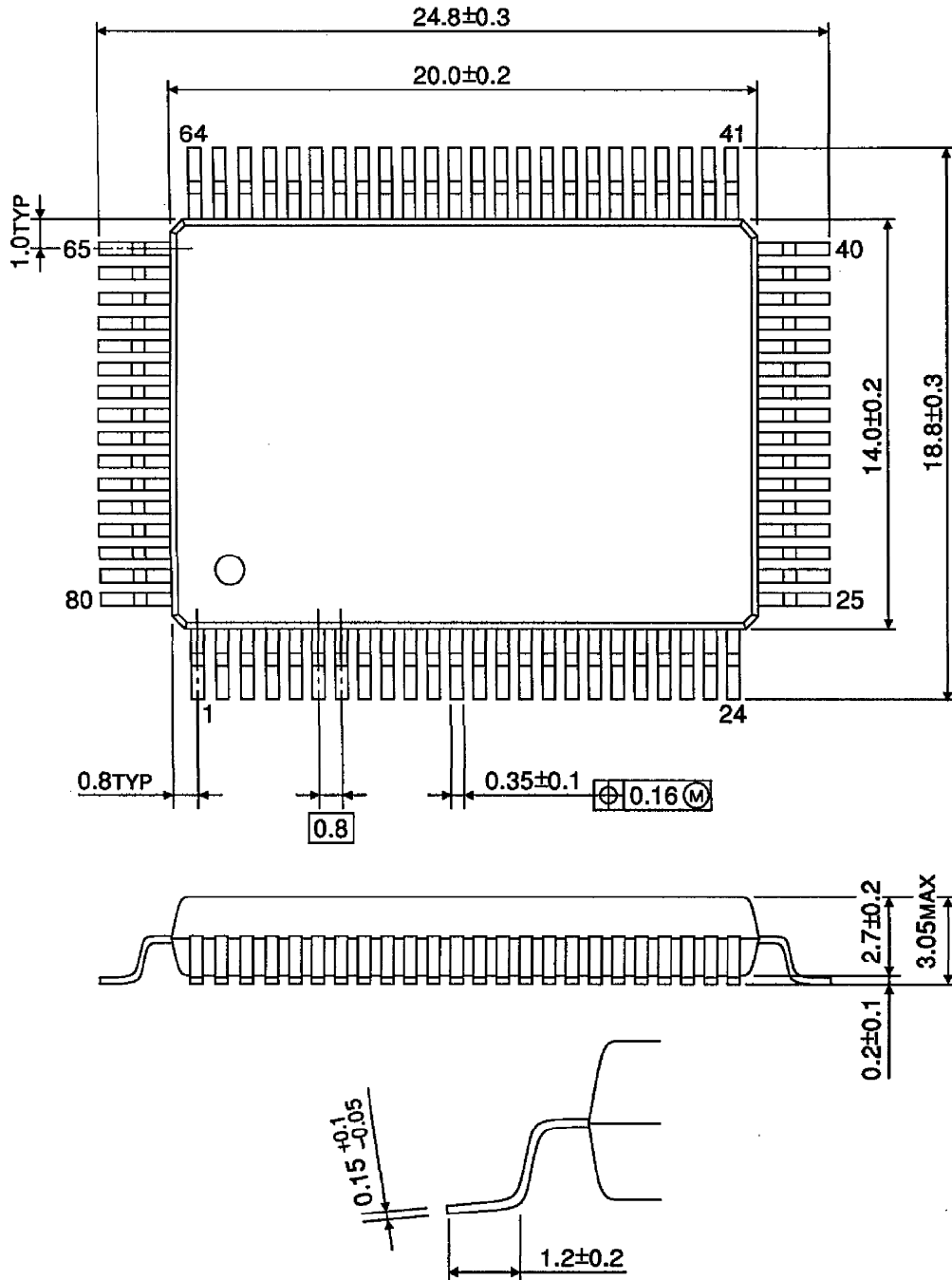


(Cautions)

- Quality of crystal oscillation wave form largely affect S/N ratio and noise distortion. Further, this is also true then system clock is input externally through the XI terminal.
- The wiring between the TC9284BF output and the TA2009F input must be made the shortest.
- The condenser between V_{DD} and GND shall be connected as close to the pin as possible.

OUTLINE DRAWING
QFP80-P-1420-0.80A

Unit : mm



Weight : 1.57g (Typ.)